TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC4093BP,TC4093BF,TC4093BFN

TC4093B Quad 2-Input NAND Schmitt Triggers

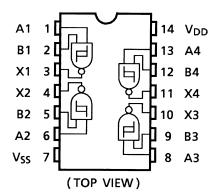
The TC4093B is a quad 2-input NAND gate having Schmitt trigger function for all the input terminals.

Since the circuit threshold voltage varies with rising time and falling time of the input waveform (Vp and V_N), this gate can be used for a wide variety of applications to line receivers, waveform shaping, astable multivibrators, monosatable multivibrators, etc.

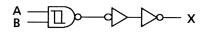
In additon to regular NAND gates.

As the TC4093B and the TC4011B are identical in pin assignment, they are compatible each other.

Pin Assignment

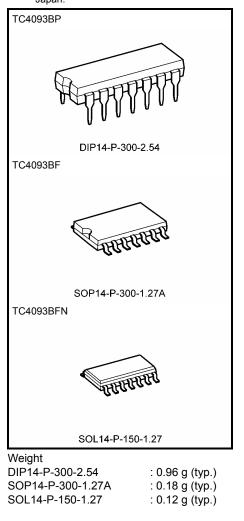


Logic Diagram

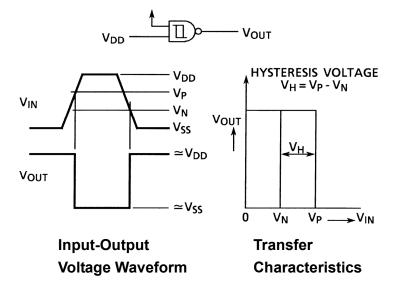


 $X = \overline{A \cdot B}$

Note: xxxFN (JEDEC SOP) is not available in Japan.



Input-Output Characteristic



Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
DC supply voltage	V _{DD}	$V_{SS}-0.5\text{-}V_{SS}+20$	V
Input voltage	V _{IN}	$V_{SS}-0.5\text{-}V_{DD}+0.5$	V
Output voltage	V _{OUT}	$V_{SS}-0.5V_{DD}+0.5$	V
DC input current	I _{IN}	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T _{opr}	-40~85	°C
Storage temperature range	T _{stg}	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (V_{SS} = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	V _{DD}	—	3	—	18	V
Input voltage	V _{IN}	—	0		V _{DD}	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either V_{DD} or V_{SS} .

Static Electrical Characteristics (V_{SS} = 0 V)

Characteristics Symbol		Svm-	Test Condition		-40°C		25°C			85°C		
				V _{DD} (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
		V _{OH}	I _{OUT} < 1 μΑ	5	4.95		4.95	5.00		4.95		
High-level output voltage	$ _{OUT} < 1 \mu A$ VIN = VSS, VDD		10	9.95	—	9.95	10.00	—	9.95	—	V	
			$v_{IN} = v_{SS}, v_{DD}$	15	14.95	—	14.95	15.00	—	14.95	_	
			I _{OUT} < 1 μA	5	—	0.05		0.00	0.05	—	0.05	
Low-level voltage	output	VOL	$V_{IN} = V_{DD}$	10	—	0.05	—	0.00	0.05	—	0.05	V
Ū				15	—	0.05		0.00	0.05	—	0.05	
			$V_{OH} = 4.6 V$	5	-0.61		-0.51	-1.0	—	-0.42	—	mA
			$V_{OH} = 2.5 V$	5	-2.50		-2.10	-4.0	—	-1.70	—	
Output hig	h current	IOH	$V_{OH} = 9.5 V$	10	-1.50	—	-1.30	-2.2	—	-1.10	—	
			V _{OH} = 13.5 V	15	-4.00		-3.40	-9.0	—	-2.80	—	
			$V_{IN}=V_{SS},V_{DD}$									
			$V_{OL} = 0.4 \ V$	5	0.61	_	0.51	1.5	_	0.42	_	mA
Output los	ourrent		$V_{OL} = 0.5 \ V$	10	1.5	_	1.30	3.8	_	1.10	—	
Output low current	I _{OL}	$V_{OL} = 1.5 V$	15	4.0	_	3.40	15.0	_	2.80	—	IIIA	
		$V_{IN} = V_{DD}$										
		VP	$V_{OUT} = 0.5 V, 4.5 V$	5	_	_	2.05	2.8	3.55	_	_	v
High thres voltage	hold		$V_{OUT} = 1.0 V, 9.0 V$	10	—	—	4.10	5.3	7.00	—	—	
voltage			$V_{OUT} = 1.5 V, 13.5 V$	15	_	_	6.20	7.8	10.40	—	—	
			$V_{OUT} = 0.5 V, 4.5 V$	5	_	_	1.5	2.3	3.15	_	_	
Low thresh voltage	hold	V _N	$V_{OUT} = 1.0 V, 9.0 V$	10	—		3.2	4.5	6.30	—	—	V
			$V_{OUT} = 1.5 V, 13.5 V$	15	—		4.8	6.6	9.30	—	—	
Hysteresis voltage		V _H	_	5	_	_	0.20	0.5	0.85	_	_	
				10	_	_	0.30	0.8	1.40	—	—	V
				15	_	_	0.45	1.2	1.90	—	—	
Input	"H" level	IIH	V _{IH} = 18 V	18	_	0.1		10 ⁻⁵	0.1	_	1.0	μA
current	"L" level	ΙĮĽ	$V_{IL} = 0 V$	18		-0.1		-10 ⁻⁵	-0.1		-1.0	μΑ
	•		$V_{IN} = V_{SS}, V_{DD}$	5	_	1		0.001	1	_	7.5	
Quiescent current	supply	I _{DD}		10	—	2		0.002	2	_	15.0	μA
			(Note)	15	_	4		0.004	4	—	30.0	

Note: All valid input combinations.

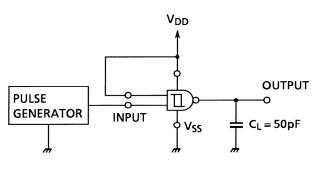
Dynamic Electrical Characteristics (Ta = 25°C, V_{SS} = 0 V, C_L = 50 pF)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Characteristics	Symbol		V _{DD} (V)		тур.	IVIAX	Unit
Output transition time	tт∟н		5	_	80	200	
		—	10	—	50	100	ns
(low to high)			15	—	40	80	
Output transition time	tтнL		5	_	80	200	
Output transition time (high to low)		—	10	—	50	100	ns
			15	—	40	80	
	tр∟н tрн∟		5	_	130	260	
Propagation delay time		_	10	—	60	120	ns
			15	_	40	80	
Input capacitance	C _{IN}			5	7.5	pF	

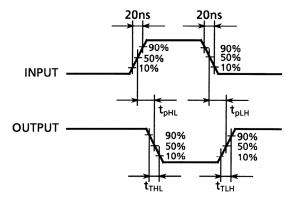
Waveform

Circuit and Waveform for Measurement of Dynamic Characteristics

Circuit



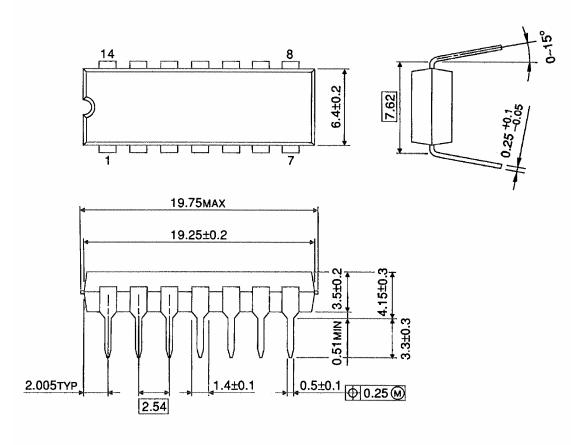
DUTY RATIO = 50%, f = 500 kHz



Package Dimensions

DIP14-P-300-2.54

Unit : mm

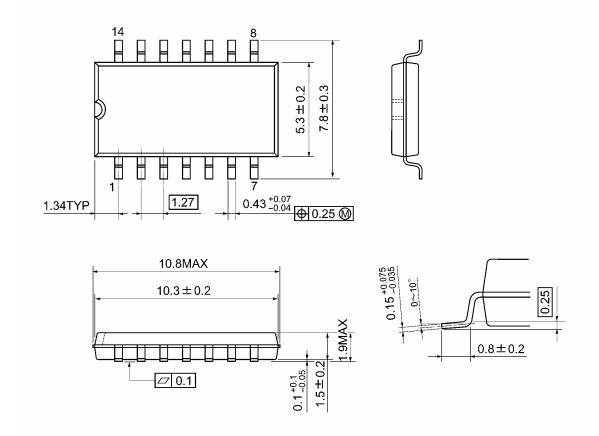


Weight: 0.96 g (typ.)

Package Dimensions

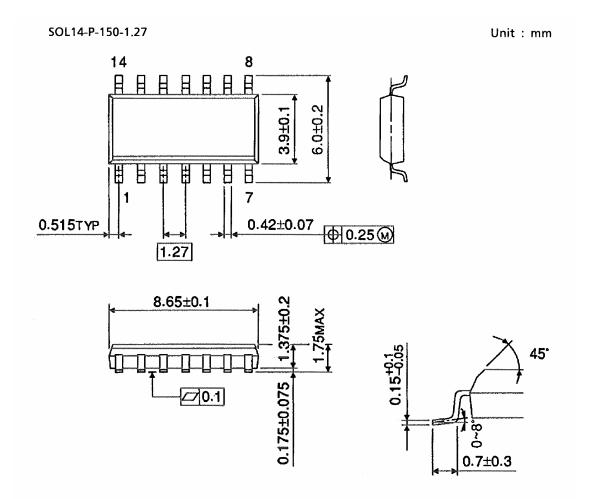
SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

2007-10-01

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20070701-EN GENERAL

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